

**Search Notes**

Applicati n/Contr l No.

10/631,346

Examin r

Tan V. Mai

Applicant(s)/Pat nt under  
Reexaminati n

AGRAWAL ET AL.

Art Unit

2193

**SEARCHED**

Class	Subclass	Date	Examiner
708	200	7/10/2006	MAI

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	7/10/2006	MAI